

A novel random approach to diagnostic test generation

Osimiry, Emmanuel Ovie; Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan 2nd IEEE NORCAS Conference : 1-2 November 2016, Copenhagen, Denmark 2016 / [4] p. : ill <https://doi.org/10.1109/NORCHIP.2016.7792915>

A tool for random test generation targeting high diagnostic resolution

Osimiry, Emmanuel Ovie; Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 79-82 : ill http://www.eester.ee/record=b2150914*est

Versatile direct and transpose matrix multiplication with chained operations : an optimized architecture using circulant matrices

lakymchuk, Taras; Rosado-Munoz, Alfredo; Mompean, Manuel Bataller; Villora, Jose Vicente Frances; **Osimiry, Emmanuel Ovie** IEEE Transactions on Computers 2016 / p. 3470 - 3479 <https://doi.org/10.1109/TC.2016.2538235> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)